

Notice of References Cited	Application/Control No. 10/042,080		Applicant(s)/Patent Under Reexamination BERRY ET AL.	
	Examiner John P Trimmings		Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,490,702	12-2002	Song et al.	714/726
	B	US-6,678,846	01-2004	Maeno, Hideshi	714/726
	C	US-6,529,033	03-2003	Park et al.	326/16
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Woytowich et al., "Delay Test of Chip I/Os Using LSSD Boundary Scan", 18-23 October 1998, IEEE Test Conference Proceedings, pp 83-90.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.